

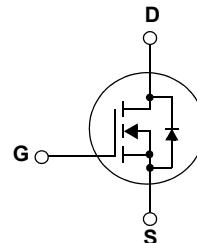
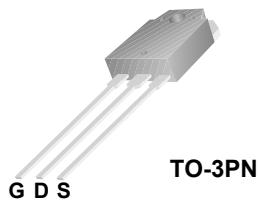
# FDA33N25

## N-Channel MOSFET

### 250V, 33A, 0.094Ω

#### Features

- $R_{DS(on)} = 0.088\Omega$  (Typ.) @  $V_{GS} = 10V$ ,  $I_D = 16.5A$
- Low gate charge (Typ. 36nC)
- Low  $C_{rss}$  (Typ. 35pF)
- Fast switching
- Improved dv/dt capability
- RoHS compliant



#### Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.

#### MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
$V_{DSS}$	Drain to Source Voltage		250	V
$V_{GSS}$	Gate to Source Voltage		$\pm 30$	V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ C$ )	33	A
		-Continuous ( $T_C = 100^\circ C$ )	21	
$I_{DM}$	Drain Current	- Pulsed	(Note 1)	132
$E_{AS}$	Single Pulsed Avalanche Energy		918	mJ
$I_{AR}$	Avalanche Current		(Note 1)	33
$E_{AR}$	Repetitive Avalanche Energy		(Note 1)	24.6
$dv/dt$	Peak Diode Recovery $dv/dt$		(Note 3)	V/ns
$P_D$	Power Dissipation	( $T_C = 25^\circ C$ )	245	W
		- Derate above $25^\circ C$	1.96	
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ C$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	$^\circ C$

#### Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.51	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.24	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDA33N25	FDA33N25	TO-3PN	-	-	50

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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### Off Characteristics

$\text{BV}_{\text{DSS}}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	250	-	-	V
$\Delta \text{BV}_{\text{DSS}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}, \text{Referenced to } 25^\circ\text{C}$	-	0.34	-	$\text{V}/^\circ\text{C}$
$I_{\text{DS}}^{\text{SS}}$	Zero Gate Voltage Drain Current	$V_{DS} = 250\text{V}, V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{DS} = 200\text{V}, T_C = 125^\circ\text{C}$	-	-	10	
$I_{\text{GSS}}$	Gate to Body Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

### On Characteristics

$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(\text{on})}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 16.5\text{A}$	-	0.088	0.094	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 20\text{V}, I_D = 16.5\text{A}$ (Note 4)	-	24.2	-	S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	1655	2200	pF	
$C_{oss}$	Output Capacitance		-	315	420	pF	
$C_{rss}$	Reverse Transfer Capacitance		-	35	55	pF	
$Q_g(\text{tot})$	Total Gate Charge at 10V		-	36	46.8	nC	
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 200\text{V}, I_D = 33\text{A}$ $V_{GS} = 10\text{V}$	-	10.8	-	nC	
$Q_{gd}$	Gate to Drain "Miller" Charge		(Note 4, 5)	-	16	-	nC

### Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 125\text{V}, I_D = 33\text{A}$ $R_G = 25\Omega$	-	33	76	ns
$t_r$	Turn-On Rise Time		-	142	293	ns
$t_{d(off)}$	Turn-Off Delay Time		-	77	165	ns
$t_f$	Turn-Off Fall Time		(Note 4, 5)	-	68	146

### Drain-Source Diode Characteristics

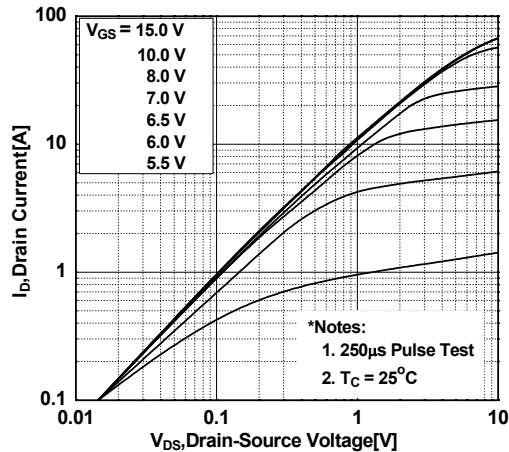
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	33	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	132	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 33\text{A}$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 33\text{A}$	-	256	-	ns
$Q_{rr}$	Reverse Recovery Charge	$dI/dt = 100\text{A}/\mu\text{s}$	(Note 4)	-	2.3	$\mu\text{C}$

**Notes:**

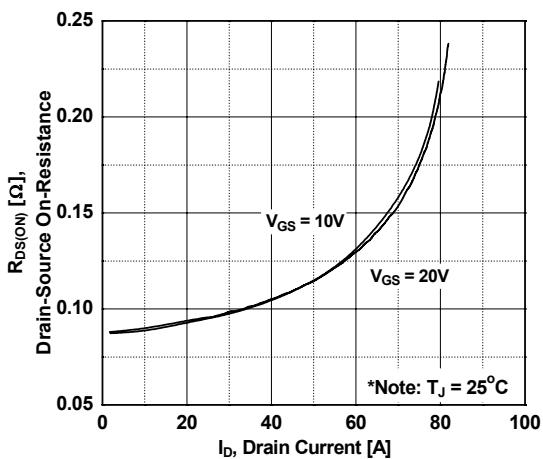
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. L = 1.35mH,  $I_{AS} = 33\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 33\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

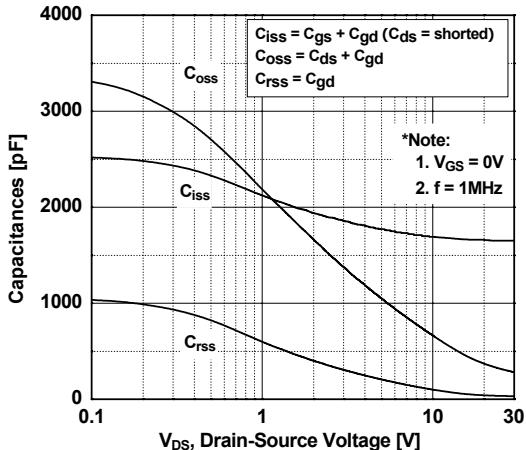
**Figure 1. On-Region Characteristics**



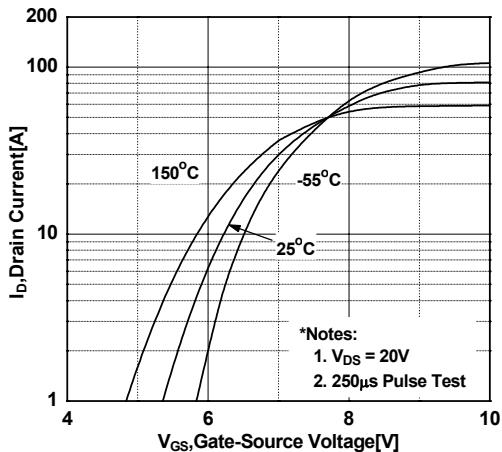
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



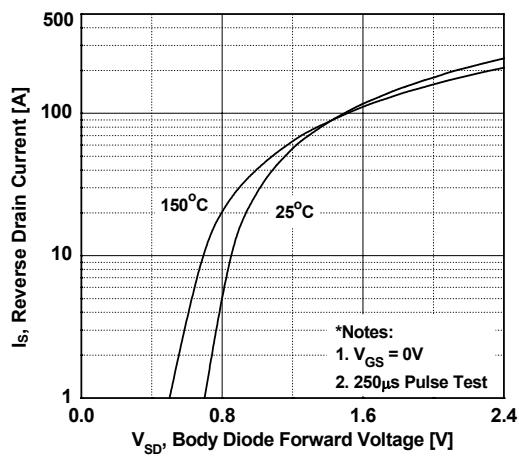
**Figure 5. Capacitance Characteristics**



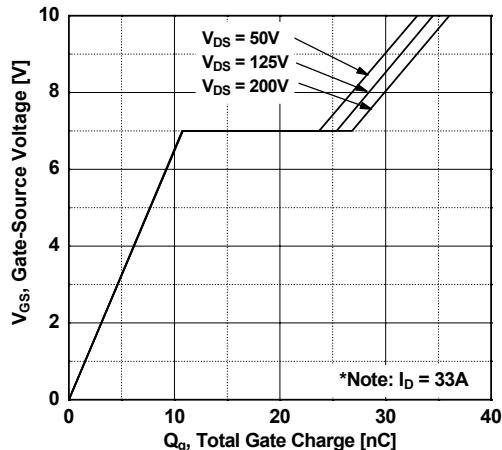
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

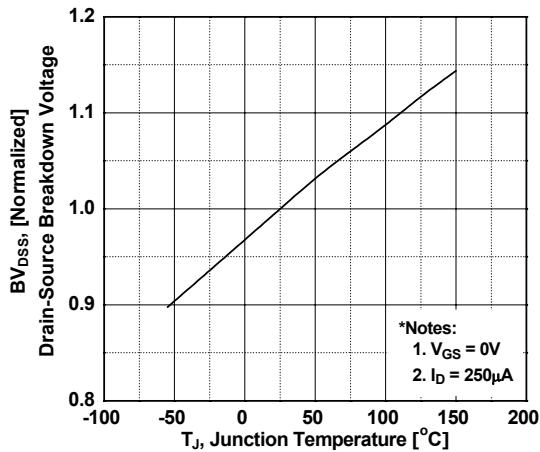


**Figure 6. Gate Charge Characteristics**

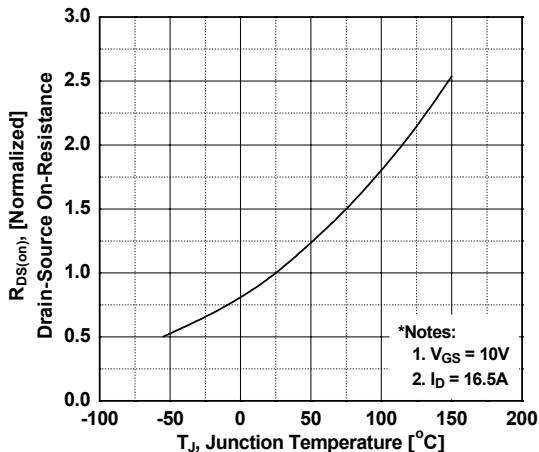


## Typical Performance Characteristics (Continued)

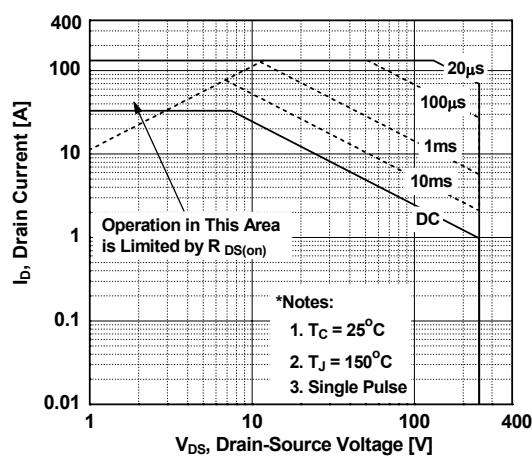
**Figure 7. Breakdown Voltage Variation vs. Temperature**



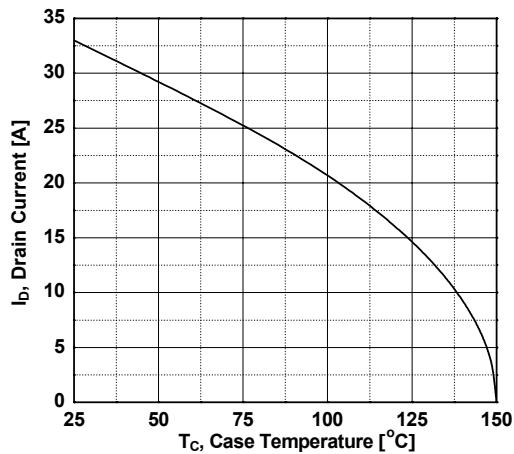
**Figure 8. On-Resistance Variation vs. Temperature**



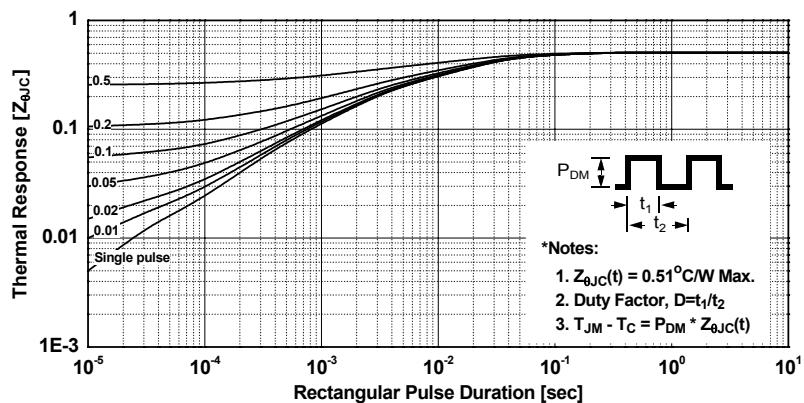
**Figure 9. Maximum Safe Operating Area**



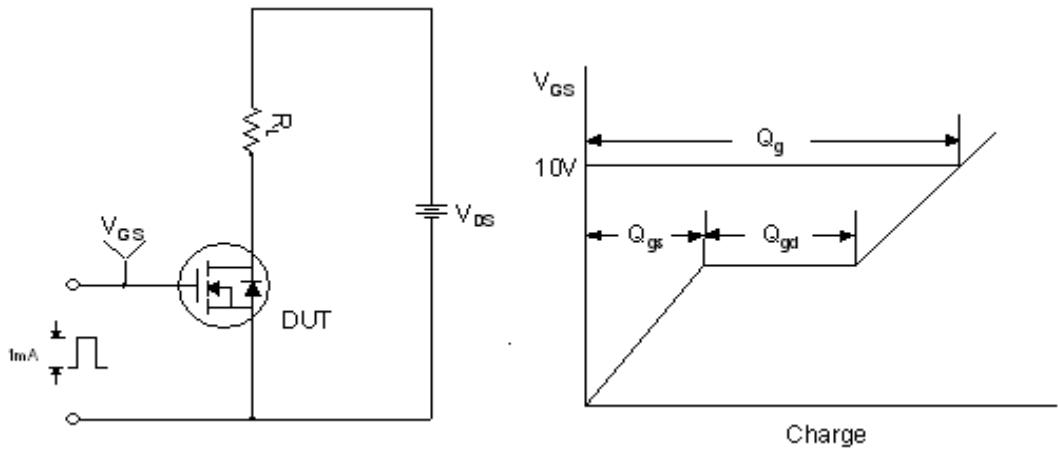
**Figure 10. Maximum Drain Current vs. Case Temperature**



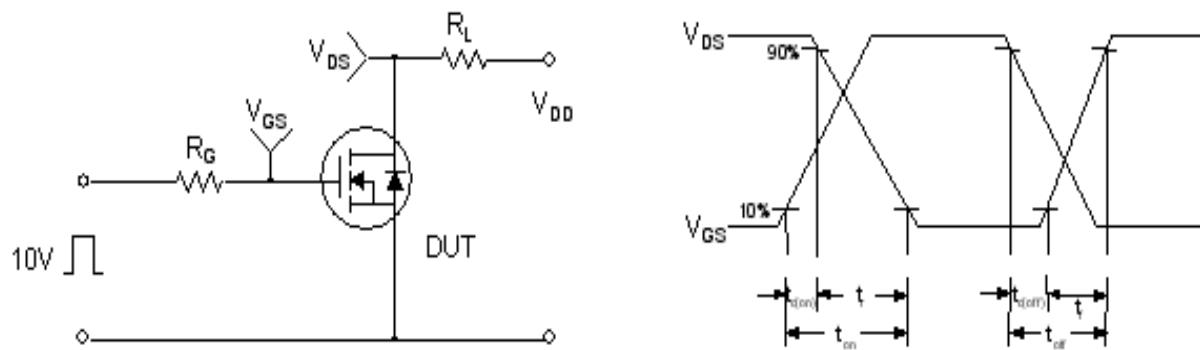
**Figure 11. Transient Thermal Response Curve**



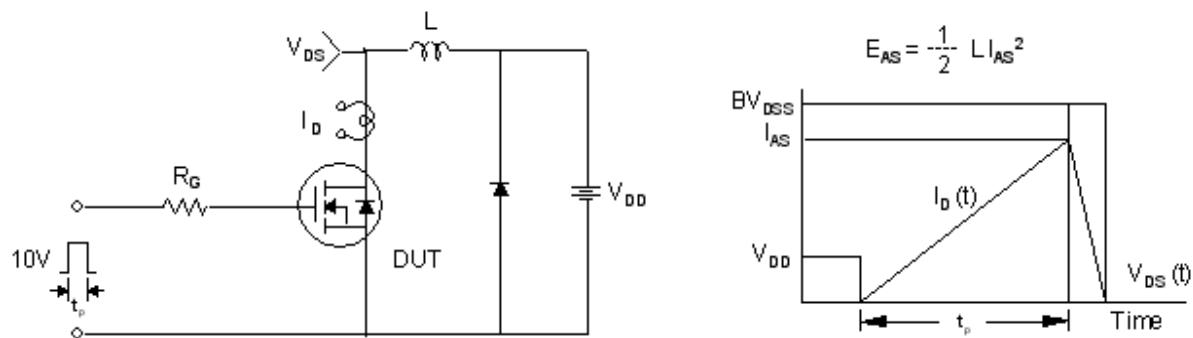
Gate Charge Test Circuit & Waveform



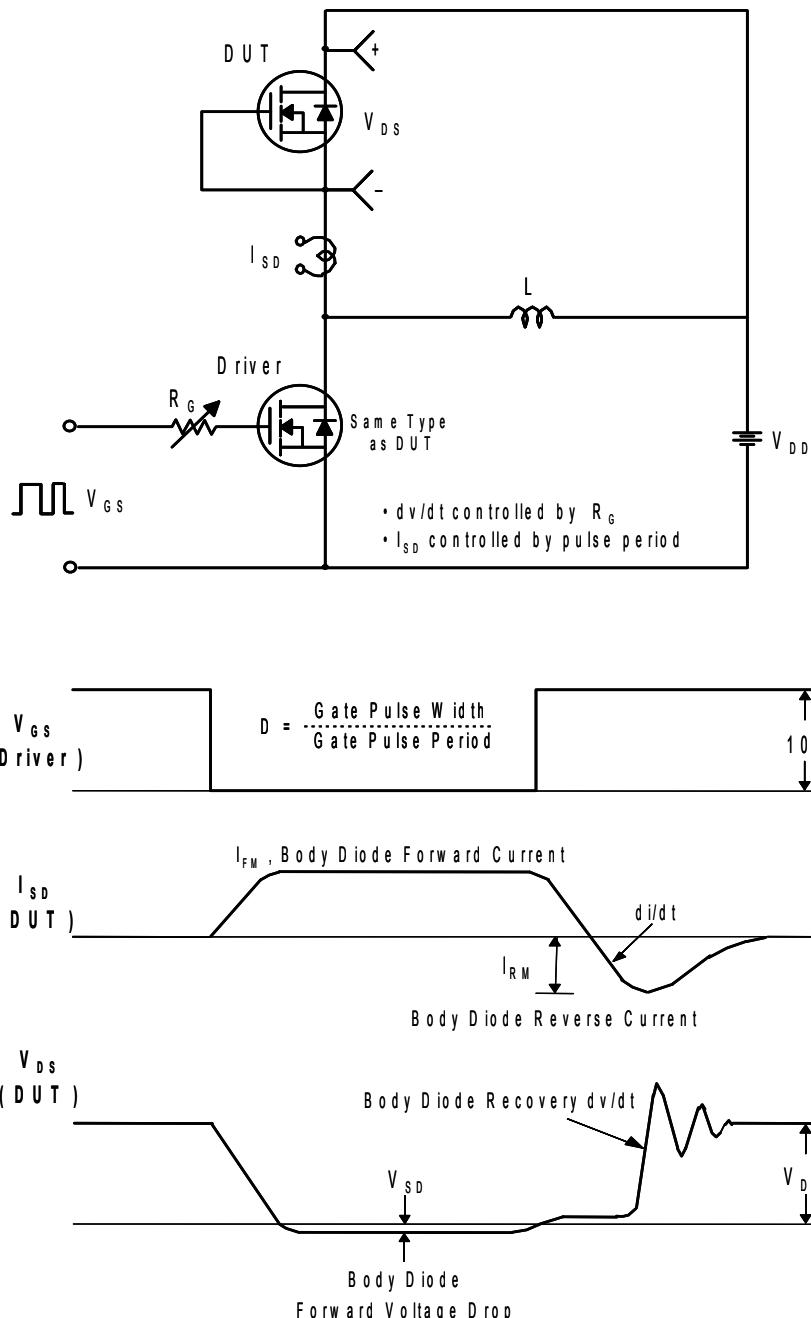
Resistive Switching Test Circuit & Waveforms

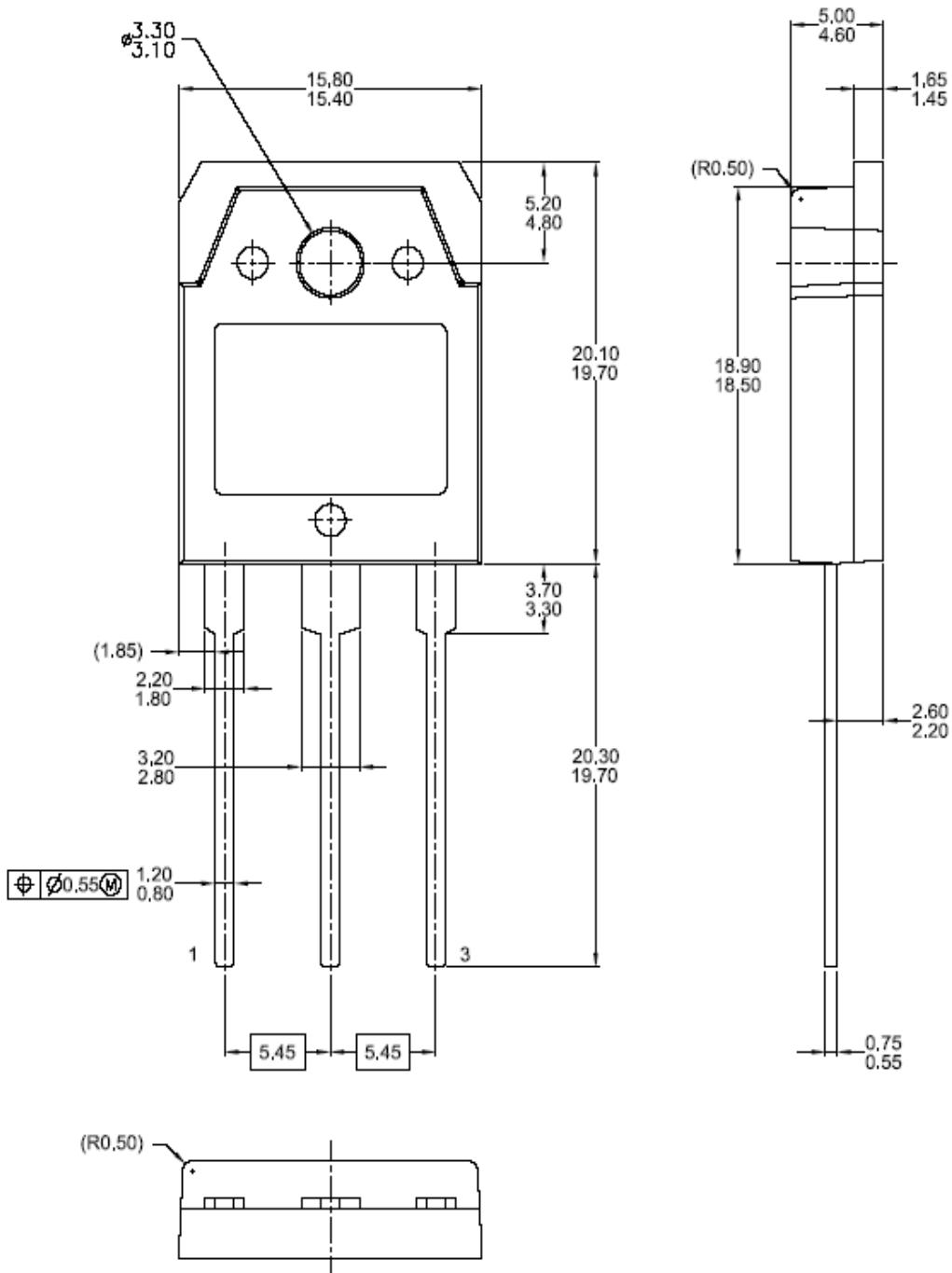


Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms



**Mechanical Dimensions****TO-3PN**

Dimensions in Millimeters



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